EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L5	3280	jitter with pll	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L6	336	jitter with pll with vco	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L7	0	input adj ports and output adj ports and eqializ$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L8	3498	input adj ports and output adj ports and equaliz$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L9	169	input adj ports with output adj ports with equaliz$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L10	0	input adj ports with output adj ports with equaliz$5 with loss and swith with matrix	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L11	0	input adj ports with output adj ports with equaliz$5 with loss and switch with matrix	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L12	63852	hasegawa.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

L13	358	asymmetrical with compression	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L14	231	access with request with memory with throughput	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L15	73	access adj request with memory with throughput	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L16	0	switch$3 near matrix with equaliz$6 with jitter with loss	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L17	4	switch$3 near matrix with equaliz$6 and jitter and loss	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L18	0	equaliz$6 with inductance with ressistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L19	0	equaliz$6 with inductor with ressistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L20	0	equaliz$6 same inductor same ressistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

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L21	82054	switch$4 and induct$4 and resistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L22	1648	375/229	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:16
L23	611	switch near matrix and equaliz$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L24	2038	375/232	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L25	1	"10/066019"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L26	1	"10/091503"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L27	1	equaliz$6 and inductor and ressistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L28	1	equaliz$6 with inductor with resistor and switch$4 and skin	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

L29	8	"6236524".pn. "6137832".pn. "6005892".pn. "4727578".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L30	16	switch adj matrix with equaliz$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L31	14	input adj ports with output adj ports with equaliz$5 with loss	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L32	6	input adj ports same output adj ports same equaliz$5 same loss and switch with matrix	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L33	62	switch with matrix and equaliz$5 with loss	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L34	2	"5191431".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L35	52	asymmetrical adj compression	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L36	46	access adj request near memory with throughput	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

L37	4	access adj request near memory near throughput	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L38	3	"10091503"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L39	25	switch near matrix with equaliz$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L40	12	switch near matrix with equaliz$6 and induc$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
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L42	3	switch$4 and induct$4 and ressistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L43	58	equaliz$6 with inductor with resistor and switch$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L44	11	equaliz$6 with inductor with resistor with switch$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

L45	12	L22 and L23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:16
L46	5	L23 and L24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L47	137	equaliz$6 with inductor with resistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L48	137	equaliz$6 with inductor with resistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L49	0	on adj chip with measurement with jitter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L50	35	chip with measurement with jitter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L51	0	chip with measurement with jitter with equaliz$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L52	0	chip with measurement with jitter same equaliz$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

L53	0	chip with measurement with jitter and equaliz$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L54	0	chip with measurement with jitter and (cross with switch$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L55	1807857	tion	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L56	0	chip with measurement with jitter and ISI	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L57	0	chip with measurement with jitter and (ISI or equaliz$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L58	5	chip with measurement same jitter and (ISI or equaliz$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L59	40	chip with measurement and jitter and (ISI or equaliz$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06
L60	9	jitter with pll with vco with measurement	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:06

L61	120	equaliz$5 with cross with switch	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:11
L62	13	equaliz$5 with crosspoint with switch	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:25
L63	297	375/271	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:16
L64	2	L23 and L63	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:17
L67	8	(equaliz$5 and crosspoint and switch).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:31
L68	1	(equaliz$5 same crosspoint same switch).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:31
L69	1	(equaliz$5 and jitter and switch and matrix).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:31
L70	1	(equaliz$5 and crosspoint and switch and jitter).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/22 18:31

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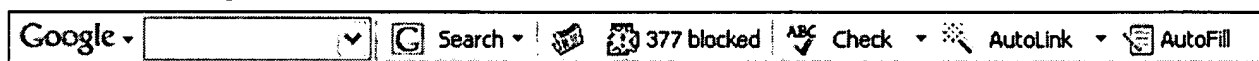OPTICAL delay line [Madsen 1999, Lenz]. ...
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KIM, Seongwon / SOMA, Mani / UNIVERSITY OF WASHINGTON, *PATENT COOPERATION TREATY APPLICATION,* Mar 2001
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☐ **16.** Mixed-signal on-chip timing measurements
Soma, M., *Integration, the VLSI Journal,* Dec 1998
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